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AEHR TEST SYSTEMS ANNOUNCES MAX4 SYSTEM SALE TO ASE TEST

FREMONT, CA (September 25, 2001) – Aehr Test Systems (Nasdaq: AEHR), a leading supplier of test and burn-in equipment to semiconductor manufacturers, today announced that ASE Test Limited (Nasdaq: ASTSF), a subsidiary of ASE Inc. (NYSE: ASX), has purchased multiple MAX4 systems.

ASE Inc., based in Taiwan, is one of the world's largest independent providers of semiconductor packaging services and, together with its subsidiary ASE Test Limited (ASET), is one of the world's largest independent providers of semiconductor testing services, including front-end engineering testing, wafer probing and final testing services.

C.J. Meurell, president and chief operating officer of Aehr Test, said, “As a long time user of Aehr Test products, ASET understands technology features versus cost per DUT trade offs in the highly competitive burn-in services market. The technology that went into the creation of the MAX4 system provides a higher power burn-in system at a lower cost per DUT.”

Many of today’s logic ICs, such as microprocessors and digital signal processors, are providing more functions per chip and operating at increasingly faster clock speeds, resulting in more current and more power being consumed per IC. The MAX4 system offers both higher current per device and the ability to control the temperature of higher power devices.

“The MAX4 system handles up to 150 amps per burn-in board, so it fills the needs of some of our customers like ASET, who want a lower cost burn-in solution for higher power components,” said Carl Buck, Aehr Test’s vice president of marketing.

The trend-setting features of other members of the MAX family of test and burn-in systems, such as low-voltage capabilities for today’s leading-edge IC processes and functional testing capabilities for using on-chip BIST (built-in self-test), are incorporated into the MAX4.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,000 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX™, MTX, MAX3 and MAX4

systems and the DiePak[®] carrier. The FOX is a full wafer contact burn-in and test system. The MTX is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX systems can effectively burn-in and functionally test sophisticated devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding industry growth and customer demand for the Company's products. Actual results may vary from projected results. These risks and uncertainties include economic conditions in Asia and elsewhere, world events, acceptance by customers of the MTX, MAX and DiePak technologies, the Company's development and manufacture of a commercially successful wafer-level burn-in system, and the potential emergence of alternative technologies, which could adversely affect demand for the Company's products in fiscal year 2002. See the Company's 10-K report filed with the SEC for additional risks affecting the Company.

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